


<b>Search Notes</b> 	<b>Application/Control No.</b> 10056437	<b>Applicant(s)/Patent Under Reexamination</b> CHO ET AL.
	<b>Examiner</b> Lee, Shun	<b>Art Unit</b> 2884

SEARCHED			
Class	Subclass	Date	Examiner
250	338.4	6/9/2005	/SL/
257	22	6/9/2005	/SL/
257	194	6/9/2005	/SL/
438	57	6/9/2005	/SL/
Above	UPDATED	2/22/2006	/SL/
Above	UPDATED	6/15/2006	/SL/
Above	UPDATED	6/21/2007	/SL/

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	6/21/2007	/SL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner